ON Semiconductor

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Power MOSFET

30 V, 10.3 A, Single N-Channel, SO-8

Features

- Low R_{DS(on)}
- Low Gate Charge
- Standard SO-8 Single Package
- Pb-Free Package is Available

Applications

- Notebooks, Graphics Cards
- Synchronous Rectification
- High Side Switch
- DC-DC Converters

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	30	V
Gate-to-Source Voltage			V_{GS}	±20	V
Continuous Drain	Steady	T _A = 25°C	I _D	8.6	Α
Current (Note 1)	State	T _A = 85°C		6.2	
	t ≤ 10 s	T _A = 25°C		10.3	
Power Dissipation (Note 1)	Steady State	T _A = 25°C	P _D	1.5	W
	t ≤ 10 s			2.2	
Continuous Drain	Steady	T _A = 25°C	Ι _D	6.4	Α
Current (Note 2)	State	T _A = 85°C		4.6	
Power Dissipation (Note 2)		T _A = 25°C	P _D	0.83	W
Pulsed Drain Current t _p = 10 μs			I _{DM}	31	Α
Operating Junction and Storage Temperature			T _J , T _{stg}	–55 to 150	°C
Source Current (Body Diode)			I _S	2.1	Α
Single Pulse Drain-to-Source Avalanche Energy (V _{DD} = 25 V, V _{GS} = 10 V, I _L Peak = 7.5 A, L = 10 mH, R _G = 25 Ω)			E _{AS}	150	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	83.5	°C/W
Junction–to–Ambient – t ≤ 10 s (Note 1)	$R_{\theta JA}$	58	
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	150	

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

- 1. Surfacemounted on FR4 board using 1 in sq pad size (Cu area = 1.127 in sq [1 oz] including traces).
- 2. Surfacemounted on FR4 board using the minimum recommended pad size.

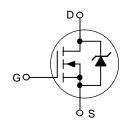


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V _{(BR)DSS}	R _{DS(ON)} TYP	I _D MAX (Note 1)
30 V	9.0 mΩ @ 10 V	10.3 A
	11.4 mΩ @ 4.5 V	10.5 A

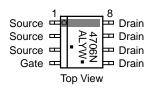
N-Channel



MARKING DIAGRAM/ **PIN ASSIGNMENT**



CASE 751 STYLE 12



4706N = Device Code = Assembly Location

= WaferLot = Year WW = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMS4706NR2	SO-8	2500/Tape & Reel
NTMS4706NR2G	SO-8 (Pb-Free)	2500/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

Techniques Reference Manual, SOLDERRM/D.

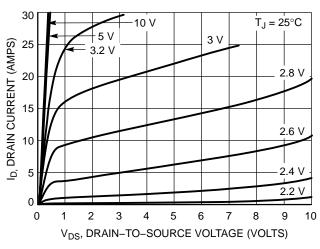
*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•		L			•	
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				21		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}		T _J = 25°C			1.0	μΑ
		V _{GS} = 0 V, V _{DS} = 24 V	T _J = 125°C			50	1
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} =				±100	nA
ON CHARACTERISTICS (Note 3)	•		•		•	•	•
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = 2$	250 μΑ	1.0		2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				-4.8		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D =	10.3 A		9.0	12	mΩ
		V _{GS} = 4.5 V, I _D =	= 10 A		11.4	15	1
Forward Transconductance	9FS	V _{DS} = 15 V, I _D =	= 10 A		19		S
CHARGES, CAPACITANCES AND GA	ATE RESISTAI	NCE	<u> </u>				
Input Capacitance	C _{iss}				950		pF
Output Capacitance	C _{oss}	V _{GS} = 0 V, f = 1.0 MHz	, V _{DS} = 24 V		400		1
Reverse Transfer Capacitance	C _{rss}	, 66 - 7 - 7 - 56			100		7
Total Gate Charge	Q _{G(TOT)}				10	15	nC
Threshold Gate Charge	Q _{G(TH)}				1.25		1
Gate-to-Source Charge	Q _{GS}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15$	V, I _D = 10 A		2.4		1
Gate-to-Drain Charge	Q_{GD}				4.5		1
Gate Resistance	R _G				1.82		Ω
SWITCHING CHARACTERISTICS (No	ote 4)		<u> </u>				
Turn-On Delay Time	t _{d(on)}				7.5	12	ns
Rise Time	t _r	V _{GS} = 10 V, V _{DD} = 15 V	V. In = 1.0 A.		4.0	8.0	
Turn-Off Delay Time	t _{d(off)}	$R_G = 3.0 \Omega$	2		24	40	
Fall Time	t _f				14	25	
DRAIN-SOURCE DIODE CHARACTE	RISTICS		<u> </u>				
Forward Diode Voltage	V_{SD}		T _J = 25°C		0.74	1.0	V
		$V_{GS} = 0 \text{ V}, I_{S} = 2.1 \text{ A}$	T _J = 125°C		0.57		
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V}, d_{IS}/d_t = 100 \text{ A/}\mu\text{s},$ $I_S = 2.1 \text{ A}$			34		ns
Charge Time	ta				16		1
Discharge Time	t _b				18		1
Reverse Recovery Charge	Q _{RR}				29		nC

Pulse Test: pulse width = 300 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

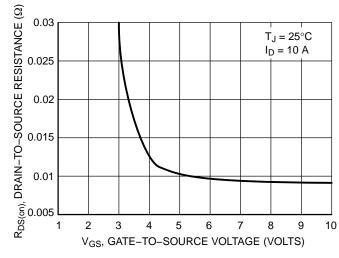
TYPICAL PERFORMANCE CURVES



35 $V_{DS} \ge 10 \text{ V}$ 30 ID, DRAIN CURRENT (AMPS) 25 20 15 $T_J = 125^{\circ}C$ 10 $T_{.1} = 25^{\circ}C$ 5 $T_J = -55^{\circ}C$ 0 1.5 3.5 1 2 2.5 3 4.5 VGS, GATE-TO-SOURCE VOLTAGE (VOLTS)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



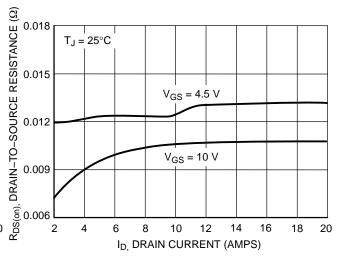
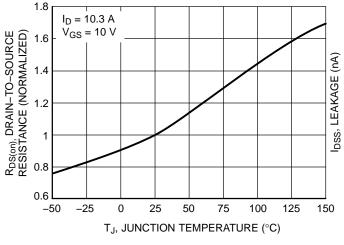


Figure 3. On–Resistance vs. Gate–to–Source Voltage

Figure 4. On–Resistance vs. Drain Current and Gate Voltage



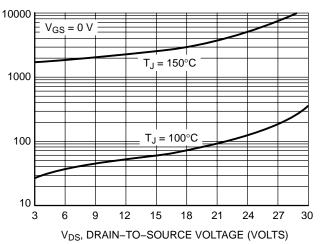
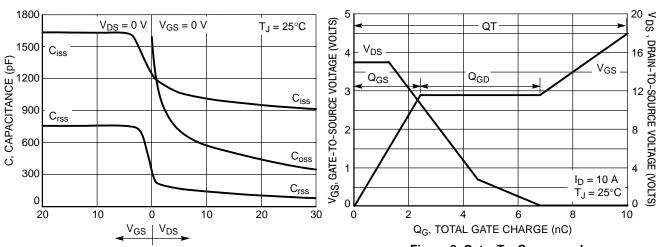


Figure 5. On–Resistance Variation with Temperature

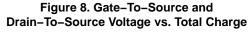
Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL PERFORMANCE CURVES



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Figure 7. Capacitance Variation



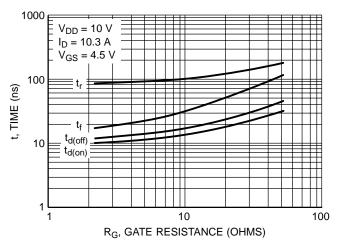


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

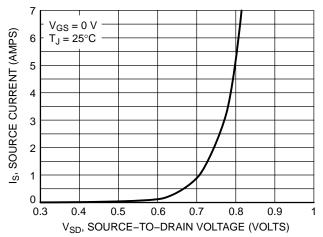
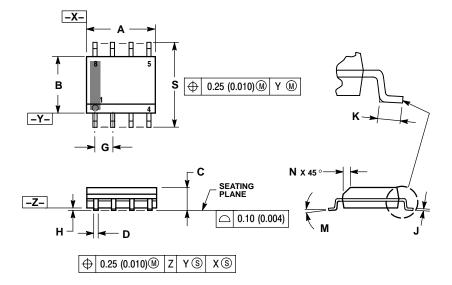


Figure 10. Diode Forward Voltage vs. Current

PACKAGE DIMENSIONS

SOIC-8 CASE 751-07 **ISSUE AG**



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: MILLIMETER.
 3. DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
 4. MAXIMUM MOLD PROTRUSION 0.15 (0.006) DED SIDE
- PER SIDE.

 5. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 6. 751–01 THRU 751–06 ARE OBSOLETE. NEW STANDARD IS 751-07.

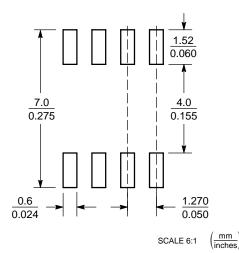
	MILLIN	IETERS	INCHES			
DIM	MIN	MAX	MIN	MAX		
Α	4.80	5.00	0.189	0.197		
В	3.80	4.00	0.150	0.157		
С	1.35	1.75	0.053	0.069		
D	0.33	0.51	0.013	0.020		
G	1.27	7 BSC	0.05	0 BSC		
Н	0.10	0.25	0.004	0.010		
J	0.19	0.25	0.007	0.010		
K	0.40	1.27	0.016	0.050		
М	0 °	8 °	0 °	8 °		
N	0.25	0.50	0.010	0.020		
S	5.80	6.20	0.228	0.244		

STYLE 12:

PIN 1. SOURCE 2. SOURCE

- SOURCE
- 4. 5. GATE DRAIN
- DRAIN
- 6. 7. 8. DRAIN DRAIN

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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